

Form PTO-1449 U.S. Department of Commerce Patent and Trademark Office				Atty. Docket No.: FMW-GG-CIP (CZ 22-CIP)		Serial No.:	
LIST OF PRIOR ART CITED BY APPLICANT (Use several sheets if necessary)				Applicant: Dr. Frederik Bijkerk et al.			
				Filing Date: November 12, 2003		Group:	

U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing date if appropriate	
GAB ↓ GAB	AA	5,052,033	September 1991	Ikeda et al.			
	AB	5,265,143	November 1993	Early et al.			
	AC	5,433,988	July 18, 1995	Fukuda et al.			
	AD	5,760,981	June 2, 1998	Gillich			
	AE	5,958,605	September 1999	Montcalm et al.			
	AF	5,310,603	May 10, 1994	Fukuda et al.			
	AG	6,160,867	December 2000	Murakami			
	AH						
	AI						
	AJ						
AK							

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation Yes No		
GAB ↓ GAB	AL	WO 99/24851	May 20, 1999	WIPO			
	AM	08122496	May 17, 1996	JP			
	AN	06273596	September 30, 1994	JP			
	AO	1 065 568 A2	January 3, 2001	EP ..			
	AP						

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
GAB ↓ GAB	AR	J.H. Underwood et al., <i>Tarnishing of Mo/Si multilayer x-ray mirrors</i> , Applied Optics, vol. 32, 1993, p. 6985-6990
↓ GAB	AS	C. Montcalm et al., <i>Multilayer reflective coatings for extreme-ultraviolet lithography</i> , SPIE, vol. 3331, (1998) p. 42-51
GAB	AT	M. Cilia et al., <i>Ni/Si based multilayer for the reflection of soft x rays in the "water window"</i> , J. Appl-Phys., 82 (9), 1997, p. 4137-4142

EXAMINER B. B. 870	DATE CONSIDERED 3/15/06
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*EXAMINER: Initial if reference considered whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
GAB	AR		H. Takenaka et al, <i>Design and fabrication of highly heat-resistant Mo/Si multilayer soft X-ray mirrors with interleaved barrier layers</i> , J. Synchrotron Rad. (1998) 5. p. 708-710				
EAB	AS		E.J. Puik et al., <i>Ion bombardment of X-ray multilayer coatings: comparison of ion etching and ion assisted deposition</i> , Applied Surface Science 47 (1991) p. 251-260				
	AT						
EXAMINER				DATE CONSIDERED			
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